Notice of References Cited Application/Control No. 10/619,758 Applicant(s)/Patent Under Reexamination VIENNEAU ET AL. Examiner Thuy Osberg Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,825,944 A	10-1998	Wang, Shin-Ywan	382/309
*	В	US-5,913,063 A	06-1999	McGurrin et al.	717/109
*	С	US-6,070,167 A	05-2000	Qian et al.	707/102
*	D	US-2002/0069218 A1	06-2002	Sull et al.	707/501.1
*	E	US-6,577,807 B1	06-2003	Yaegashi et al.	386/52
*	F	US-6,633,308 B1	10-2003	Ono et al.	715/723
*	G	US-6,714,201 B1	03-2004	Grinstein et al.	345/474
*	Н	US-6,983,420 B1	01-2006	Itou et al.	715/723
*	ı	US-2002/0051005	05-2002	Trinh et al.	345/619
*	J	US-6,130,676	10-2000	Wise et al.	345/619
*	K	US-6,343,377	01-2002	Gessner et al.	717/171
	الـ	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 9917228 A1	04-1999	World Intellect	QIAN et al.	
	0	EP 969387 A2	01-2000	European Patent	YAEGASHI et al.	
	ρ					
	σ					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
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	w						
	×						

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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